Special Issue

Nanoelectrochemistry for Single Particle Detection

Message from the Guest Editor

This Special Issue of *Applied Sciences*, "Nanoelectrochemistry for Single Particle Detection", aims to cover recent advances, original works, and new trends in single-particle electrochemistry. The topics are not limited strictly to nanoelectrochemistry but are assumed to address related fields such as the development of new materials and nanotechnologies for improving single-entity electroanalytical measurements. In this Special Issue we welcome both original research papers and review articles on diverse topics such as:

- nanoparticles
- microelectrodes
- nano-objects
- single electrochemical detection
- chronoamperometry
- low current
- electroactive species
- charge transfer
- biological and biochemical entities
- scanning electrochemical microscopy

Guest Editor

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Deadline for manuscript submissions

closed (10 February 2022)

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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